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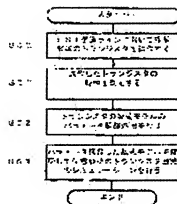
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(54) PARAMETER ADJUSTING DEVICE

(57)Abstract:

PROBLEM TO BE SOLVED: To perform an efficient and precise parameter adjustment by applying a genetic algorithm to the parameter adjustment for a physical model of a transistor.

SOLUTION: A parameter adjusting device is provided with a means for generating a new parameter gene by special crossover processing, a normalization means for applying to a parameter being a real number, and an evaluation means for evaluating the parameter so that it will match a characteristic unique to the transistor (MOSFET) highly precisely. In the above configuration, it becomes possible to apply the genetic algorithm to the parameter adjustment for the physical model of the transistor, so that an optimum parameter group can be determined in a short time and a precise circuit simulation can be performed using the parameter.



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